

IGBT³ Chip

FEATURES:

- 1200V Trench + Field Stop technology
- low turn-off losses
- short tail current
- positive temperature coefficient
- easy paralleling

This chip is used for:

power module



Applications:

drives

Chip Type	V _{CE}	I _{Cn}	Die Size	Package	Ordering Code
SIGC84T120R3	1200V	75A	9.13 x 9.15 mm ²	sawn on foil	Q67050- A4107-A001

MECHANICAL PARAMETER:

Raster size	9.13 x 9.15			
Emitter pad size	8x(1.864 x 3.736)			
Gate pad size	1.139 x 1.139			
Area total / active	83.5 / 63.6			
Thickness	140	μm		
Wafer size	150	mm		
Flat position	90	grd		
Max.possible chips per wafer	164 pcs			
Passivation frontside	Photoimide			
Emitter metallization	3200 nm AlSiCu			
Collector metallization	1400 nm Ni Ag –system suitable for epoxy and soft solder die bonding			
Die bond	electrically conductive glue or solder			
Wire bond	AI, <500μm			
Reject Ink Dot Size	Ø 0.65mm ; max 1.2mm			
Recommended Storage Environment	store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C			



MAXIMUM RATINGS:

Parameter	Symbol	Value	Unit	
Collector-emitter voltage, T_j =25 °C	V _{CE}	1200	V	
DC collector current, limited by T _{jmax}	I _C	1)	А	
Pulsed collector current, t _p limited by T _{jmax}	I _{cpuls}	225	А	
Gate emitter voltage	V _{GE}	±20	V	
Operating junction and storage temperature	T_j , T_{stg}	-55 + 150	°C	

¹⁾ depending on thermal properties of assembly

STATIC CHARACTERISTICS (tested on chip), T_j =25 °C, unless otherwise specified:

Parameter	Symbol	Conditions	Value			Unit
i arameter			min.	typ.	max.	
Collector-emitter breakdown voltage	V _{(BR)CES}	V_{GE} =0 V , I_{C} = 3 mA	1200			
Collector-emitter saturation voltage	V _{CE(sat)}	V _{GE} =15V, I _C =75A	1.4	1.7	2.1	V
Gate-emitter threshold voltage	V _{GE(th)}	$I_C=3mA$, $V_{GE}=V_{CE}$	5.0	5.8	6.5	
Zero gate voltage collector current	I _{CES}	V _{CE} =1200V , V _{GE} =0V			10.1	μA
Gate-emitter leakage current	I _{GES}	V _{CE} =0V , V _{GE} =20V			600	nA
Integrated gate resistor	R _{Gint}			10		Ω

ELECTRICAL CHARACTERISTICS (tested at component):

Parameter	Symbol	Conditions	Value			Unit
raiametei	Symbol		min.	typ.	max.	Oilit
Input capacitance	Ciss	V _{CE} =25V,		5345		pF
Output capacitance	Coss	$V_{GE}=0V$,		280		
Reverse transfer capacitance	Crss	f=1MHz		242		

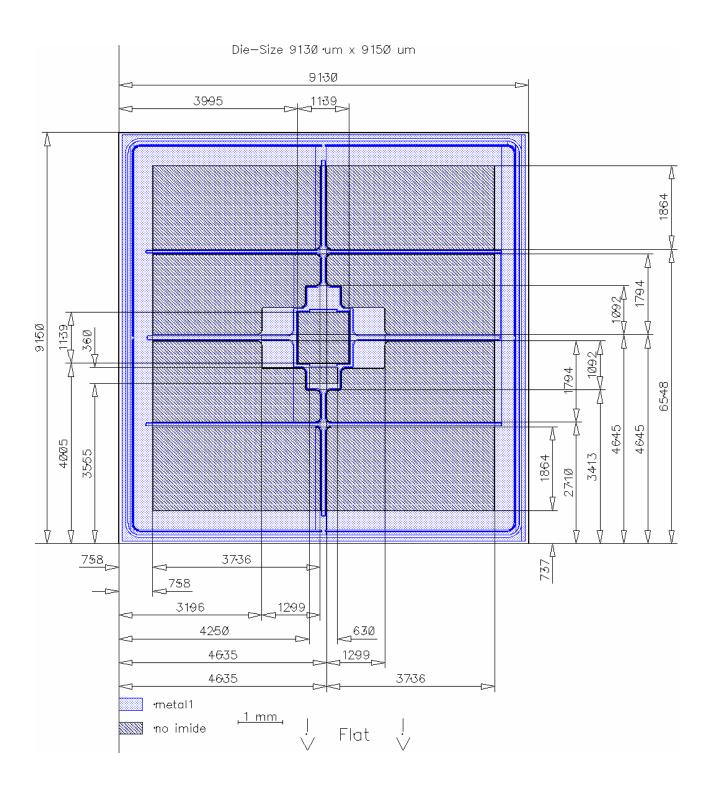
SWITCHING CHARACTERISTICS (tested at component), Inductive Load

Parameter	Symbol	Conditions 1)	Value			Unit
raiailietei	Symbol		min.	typ.	max.	Oilit
Turn-on delay time	$t_{d(on)}$	<i>T</i> _j =125°C		285		ns
Rise time	$t_{\rm r}$	V _{CC} =600V,		45		
Turn-off delay time	$t_{d(off)}$	I _C =75A, V _{GE} =-15/15V,		520		
Fall time	t_{f}	$R_{\rm G}$ = 4.7 Ω		90		

¹⁾ values also influenced by parasitic L- and C- in measurement and package.



CHIP DRAWING:





This chip data sheet refers to the device data sheet DESCRIPTION: AQL 0,65 for visual inspection according to failure catalog Electrostatic Discharge Sensitive Device according to MIL-STD 883 Test-Normen Villach/Prüffeld

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